

# Search Notes



Application/Control No.

10/538,540

Examiner

Rip A. Lee

Applicant(s)/Patent under  
Reexamination

MIHAN ET AL.

Art Unit

1796

## SEARCHED

Class	Subclass	Date	Examiner
526	172	10-14-2007	nm
526	161	10-14-2007	nm
556	53	10-14-2007	nm
526	348	10-14-2007	nm
526	396	10-14-2007	nm

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
FAST updated search	10-14-2007	nm
updated inventor search	10-14-2007	nm